

INTERNATIONAL STANDARD

QC 440000

**Thermistors – Directly heated positive temperature coefficient –
Part 1: Generic specification**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**THERMISTORS – DIRECTLY HEATED POSITIVE
TEMPERATURE COEFFICIENT –****Part 1: Generic specification**

FOREWORD

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International Standard IEC 60738-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment.

This consolidated version of IEC 60738-1 consists of the third edition (2006) [documents 40/1651/FDIS and 40/1730/RVD] and its amendment 1 (2009) [documents 40/1940/CDV and 40/1999/RVC].

The technical content is therefore identical to the base edition and its amendment and has been prepared for user convenience.

It bears the edition number 3.1.

A vertical line in the margin shows where the base publication has been modified by amendment 1.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The QC number that appears on the front cover of this publication is the specification number in the IEC Quality Assessment System for Electronic Components (IECQ).

IEC 60738 consists of the following parts, under the general title *Thermistors – Directly heated positive step-function coefficient*:

Part 1: Generic specification

Part 1-1: Blank detail specification – Current limiting application – Assessment level EZ

Part 1-2: Blank detail specification – Heating element application – Assessment level EZ

Part 1-3: Blank detail specification – Inrush current application – Assessment level EZ

Part 1-4: Blank detail specification – Sensing application – Assessment level EZ

The committee has decided that the contents of the base publication and its amendments will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this standard may be issued at a later date.

THERMISTORS – DIRECTLY HEATED POSITIVE TEMPERATURE COEFFICIENT –

Part 1: Generic specification

1 Scope

This part of IEC 60738 describes terms and methods of test for positive step-function temperature coefficient thermistors, insulated and non-insulated types typically made from ferro-electric semi-conductor materials.

It establishes standard terms, inspection procedures and methods of test for use in detail specifications for Qualification Approval and for Quality Assessment Systems for electronic components.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letter symbols to be used in electrical technology*

IEC 60050 (all parts), *International Electrotechnical Vocabulary (IEV)*

IEC 60062, *Marking codes for resistors and capacitors*

IEC 60068-1:1988, *Environmental testing – Part 1: General and guidance*
Amendment 1 (1992)

IEC 60068-2-1:1990, *Environmental testing – Part 2: Tests – Tests A: Cold*
Amendment 1 (1993)
Amendment 2 (1994)

IEC 60068-2-2:1974, *Environmental testing – Part 2: Tests – Tests B: Dry heat*
Amendment 1 (1993)

IEC 60068-2-6, *Environmental testing – Part 2: Tests – Test Fc: Vibration (sinusoidal)*

IEC 60068-2-11, *Environmental testing – Part 2: Tests – Test Ka: Salt mist*

IEC 60068-2-13, *Environmental testing – Part 2: Tests – Test M: Low air pressure*

IEC 60068-2-14:1984, *Environmental testing – Part 2: Tests – Test N: Change of temperature*
Amendment 1 (1986)

IEC 60068-2-20:1979, *Environmental testing – Part 2: Tests – Test T: Soldering*
Amendment 2 (1987)

IEC 60068-2-21, *Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices*

IEC 60068-2-27, *Environmental testing – Part 2: Tests – Test Ea and guidance: Shock*

IEC 60068-2-29, *Environmental testing – Part 2: Tests – Test Eb and guidance: Bump*

IEC 60068-2-30:2005, *Environmental testing – Part 2: Tests – Test Db: Damp heat, cyclic (12 h + 12-hour cycle)*

IEC 60068-2-45:1980, *Environmental testing – Part 2: Tests – Test XA and guidance – Immersion in cleaning solvents*

IEC 60068-2-58, *Environmental testing – Part 2-58: Tests – Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)*

IEC 60068-2-78, *Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state*

IEC 60294, *Measurement of the dimensions of a cylindrical component having two axial terminations*

IEC 60410, *Sampling plans and procedures for inspection by attributes*

IEC 60617 (all parts) [DB]¹: *Graphical symbols for diagrams*

IEC 60717, *Method for determination of the space required by capacitors and resistors with unidirectional terminations*

IEC 61249-2-7, *Materials for printed boards and other interconnecting structures – Part 2-7: Reinforced base materials clad and unclad – Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test), copper-clad*

IEC 61760-1, *Surface mounting technology – Part 1: Standard method for the specification of surface mounting components (SMDs)*

IEC QC 001002-3, *Rules of Procedure of the IEC Quality Assessment System for Electronic Components (IECQ) – Part 3: Approval procedures*

ISO 1000, *SI units and recommendations for the use of their multiples and of certain other units*

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

3.1

type

group of components having similar design features and the similarity of whose manufacturing techniques enables them to be grouped together either for qualification approval or for quality conformance inspection

They are generally covered by a single detail specification

NOTE Components described in several detail specifications, may, in some cases, be considered as belonging to the same type but they are generally covered by a single detail specification.

¹ "DB" refers to the IEC on-line database.